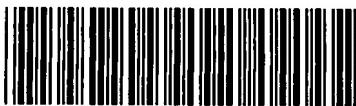


Search Notes



Application/Control No.

10/519,322

Examiner

Sam K. Ahn

**Applicant(s)/Patent under
Reexamination**

CHEN ET AL.

Art Unit

2611

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner